Designation: E 1036M – 96$^{\epsilon 2}$

METRIC

Standard Test Methods for Electrical Performance of Nonconcentrator Terrestrial Photovoltaic Modules and Arrays Using Reference Cells [Metric][1]

This standard is issued under the fixed designation E 1036M; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

ϵ^1 NOTE—Designation was corrected editorially in July 1996.
ϵ^2 NOTE—Designation was corrected editorially in December 1996.

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1. Scope

1.1 These test methods cover the electrical performance of photovoltaic modules and arrays under natural or simulated sunlight using a calibrated reference cell.

1.2 Measurements under a variety of conditions are allowed; results are reported under a select set of reporting conditions (RC) to facilitate comparison of results.

1.3 These test methods apply only to nonconcentrator terrestrial modules and arrays.

1.4 The performance parameters determined by these test methods apply only at the time of the test, and imply no past or future performance level.

1.5 There is no similar or equivalent ISO standard.

1.6 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

2. Referenced Documents

2.1 *ASTM Standards:*

E 691 Practice for Conducting an Interlaboratory Study to Determine the Precision of a Test Method[2]
E 772 Terminology Relating to Solar Energy Conversion[3]
E 891 Tables for Terrestrial Direct Normal Solar Spectral Irradiance for Air Mass 1.5[2]
E 892 Tables for Terrestrial Solar Spectral Irradiance at Air Mass 1.5 for a 37° Tilted Surface[2]
E 927 Specification for Solar Simulation for Terrestrial Photovoltaic Testing[3]
E 941 Test Method for Calibration of Reference Pyranometers With Axis Tilted by the Shading Method[2]
E 948 Test Method for Electrical Performance of Photovoltaic Cells Using Reference Cells Under Simulated Sunlight[3]
E 973 Test Method for Determination of the Spectral Mismatch Parameter Between a Photovoltaic Device and a Photovoltaic Reference Cell[3]
E 1021 Test Methods for Measuring the Spectral Response of Photovoltaic Cells[3]
E 1039 Test Method for Calibration of Silicon Non-Concentrator Photovoltaic Primary Reference Cells Under Global Irradiation[3]
E 1040 Specification for Physical Characteristics of Nonconcentrator Terrestrial Photovoltaic Reference Cells[3]
E 1125 Test Method for Calibration of Primary Nonconcentrator Terrestrial Photovoltaic Reference Cells Using a Tabular Spectrum[3]
E 1328 Terminology Relating to Photovoltaic Solar Energy Conversion[3]
E 1362 Test Method for Calibration of Nonconcentrator Photovoltaic Secondary Reference Cells[3]

3. Terminology

3.1 *Definitions*—Definitions of terms used in these test methods may be found in Terminology E 772 and Terminology E 1328.

3.2 *Definitions of Terms Specific to This Standard:*

3.2.1 *nominal operating cell temperature, NOCT, n*—the temperature of a solar cell inside a module operating at an ambient temperature of 20°C, an irradiance of 800 Wm^{-2}, and an average wind speed of 1 ms^{-1}.

3.2.2 *reporting conditions, RC, n*—the device temperature, total irradiance, and reference spectral irradiance conditions that module or array performance data are corrected to.

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[1] These test methods are under the jurisdiction of ASTM Committee E-44 on Solar, Geothermal, and Other Alternative Energy Sources and are the direct responsibility of Subcommittee E44.09 on Photovoltaic Electric Power Conversion.

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[2] *Annual Book of ASTM Standards*, Vol 14.02.

[3] *Annual Book of ASTM Standards*, Vol 12.02.

3.3 *Symbols:Symbols:*

3.3.1 The following symbols and units are used in these test methods:

α_r—temperature coefficient of reference cell I_{SC}, °C $^{-1}$,

$\alpha(E)$—current temperature function of device under test, °C^{-1},

$\beta(E)$—voltage temperature function of device under test, °C^{-1},

C—calibration constant of reference cell, Am^{2}W^{-1},

C'—adjusted calibration constant of reference cell, Am^{2}W^{-1},

C_f—NOCT Correction factor,° C,

$\delta(T)$—voltage irradiance correction function of device under test, dimensionless,

ΔT—NOCT cell-ambient temperature difference, °C,

E—irradiance, Wm^{-2},

E_o—irradiance at RC, Wm $^{-2}$,

FF—fill factor, dimensionless,

I—current, A,

I_{mp}—current at maximum power, A,

I_o—current at RC, A,

I_r—short-circuit current of reference cell, A,

I_{sc}—short-circuit current, A,

M—spectral mismatch parameter, dimensionless,

P—electrical power, W,

P_m—maximum power, W,

T—temperature, °C,

T_a—ambient temperature, °C,

T_c—temperature of cell in module, °C,

T_o—temperature at RC, °C,

T_r—temperature of reference cell, °C,

ν—wind speed, ms^{-1},

V—voltage, V,

V_{mp}—voltage at maximum power, V,

V_o—voltage at RC, V, and

V_{oc}—open-circuit voltage, V.

4. Summary of Test Methods

4.1 Measurement of the performance of a photovoltaic module or array illuminated by a light source consists of determining at least the following electrical characteristics: short-circuit current, open-circuit voltage, maximum power, and voltage at maximum power.

4.2 These parameters are derived by applying the procedure in Section 8 to a set of current-voltage data pairs (*I-V* data) recorded with the test module or array operating in the power-producing quadrant.

4.3 Testing the performance of a photovoltaic device involves the use of a calibrated photovoltaic reference cell to determine the total irradiance.

4.3.1 The reference cell is chosen according to the spectral distribution of the irradiance under which it was calibrated, for example, the direct normal or global spectrum. These spectra are defined by Tables E 891 and E 892, respectively. The reference cell therefore determines to which spectrum the test module or array performance is referred.

4.3.2 The reference cell must match the device under test such that the spectral mismatch parameter is 1.00 ± 0.05, as determined in accordance with Test Method E 973.

4.3.3 Recommended physical characteristics of reference cells are described in Specification E 1040.

4.4 The spectral response of the module or array is usually taken to be that of a representative cell from the module or array tested in accordance with Test Method E 1021. The representative cell should be packaged such that the optical properties of the module or array packaging and the representative cell package are similar.

4.5 The tests are performed using either natural or simulated sunlight. Solar simulation requirements are stated in Specification E 927.

4.5.1 If a pulsed solar simulator is used as a light source, the transient responses of the module or array and the reference cell must be compatible with the test equipment.

4.6 The data from the measurements are translated to a set of reporting conditions (see 5.3) selected by the user of these test methods. The actual test conditions, the test data (if available), and the translated data are then reported.

5. Significance and Use

5.1 It is the intent of these procedures to provide recognized methods for testing and reporting the electrical performance of photovoltaic modules and arrays.

5.2 The test results may be used for comparison of different modules or arrays among a group of similar items that might be encountered in testing a group of modules or arrays from a single source. They also may be used to compare diverse designs, such as products from different manufacturers. Repeated measurements of the same module or array may be used for the study of changes in device performance.

5.3 Measurements may be made over a range of test conditions. The measurement data are numerically translated (see Section 8) from the test conditions to SRC, to nominal operating conditions, or to optional user-specified reporting conditions. The SRC are defined in Table 1.

5.4 These test methods are based on two requirements.

5.4.1 First, the reference cell is selected so that its spectral response is considered to be close to the module or array to be tested.

5.4.2 Second, the spectral response of a representative cell and the spectral distribution of the irradiance source must be known. The calibration constant of the reference cell is then corrected to account for the difference between the actual and the reference spectral irradiance distributions using the spectral mismatch parameter, which is defined in Test Method E 973.

5.5 Terrestrial reference cells are calibrated with respect to a reference spectral irradiance distribution, for example, Tables E 891 or E 892.

5.6 A reference cell made and calibrated as described in 4.3 will indicate the total irradiance incident on a module or array whose spectral response is close to that of the reference cell.

TABLE 1 Reporting Conditions

	Total Irradiance, Wm^{-2}	Spectral Irradiance	Device Temperature,° C
Standard reporting conditions	1000	E 892	25
Nominal operating conditions	800	...	NOCT

5.7 With the performance data determined in accordance with these test methods, it becomes possible to predict module or array performance from measurements under any test light source in terms of any reference spectral irradiance distribution.

5.8 These test methods are valid for the range of temperature and irradiance conditions over which the correction factors (defined in Annex A2) were determined. Devices for which the correction factors cannot be determined or are unavailable will have to be measured at temperature and irradiance conditions as close to the desired reporting conditions as possible.

6. Apparatus

6.1 *Photovoltaic Reference Cell*—A calibrated reference cell is used to determine the total irradiance during the electrical performance measurement.

6.1.1 The reference cell shall be matched in its spectral response to a representative cell of the test module or array such that the spectral mismatch parameter as determined by Test Method E 973 is 1.00 ± 0.05.

6.1.2 Specification E 1040 provides recommended physical characteristics of reference cells.

6.1.3 Reference cells may be calibrated in accordance with Test Methods E 1039, E 1125, or E 1362, as appropriate for a particular application.

6.1.4 A current measurement instrument (see 6.7) shall be used to determine the I_{sc} of the reference cell when illuminated with the light source (see 6.4).

6.2 *Test Fixture*— The device to be tested is mounted on a test fixture that facilitates temperature measurement and four-wire current-voltage measurements (Kelvin probe, see 6.3). The design of the test fixture shall prevent any increase or decrease of the device output due to reflections or shadowing. Arrays installed in the field shall be tested as installed. See 7.2.3 for additional restrictions and reporting requirements.

6.3 *Kelvin Probe*— An arrangement of contacts that consists of two pairs of wires attached to the two output terminals of the device under test. One pair of wires is used to conduct the current flowing through the device, and the other pair is used to measure the voltage across the device. A schematic diagram of an I-V measurement using a Kelvin Probe is given in Fig. 1 of Test Method E 948.

6.4 *Light Source*— The light source shall be either natural sunlight or a solar simulator providing Class A, B, or C simulation as specified in Specification E 927.

6.5 *Temperature Measurement Equipment*—The instrument or instruments used to measure the temperature of both the reference cell and the device under test shall have a resolution of at least 0.1°C, and shall have a total error of less than ±1°C of reading.

6.5.1 Temperature sensors, such as thermocouples or thermistors, suitable for the test temperature range shall be attached in a manner that allows measurement of the device temperature. Because module and array temperatures can vary spacially under continuous illumination, multiple sensors distributed over the device should be used, and the results averaged to obtain the device temperature.

6.5.2 When testing modules or arrays for which direct measurement of the cell temperature inside the package is not feasible, sensors can be attached to the rear side of the devices. The error due to temperature gradients will depend on the thermal characteristics of the packaging, especially under continuous illumination. Modules with glass back sheets will have higher gradients than modules with thin polymer backs, for example.

6.6 *Variable Load*— An electronic load, such as a variable resistor, a programmable power supply, or a capacitive sweep circuit, used to operate the device to be tested at different points along its *I-V* characteristic.

6.6.1 The variable load should be capable of operating the device to be tested at an *I-V* point where the voltage is within 1 % of V_{oc} in the power-producing quadrant.

6.6.2 The variable load should be capable of operating the device to be tested at an *I-V* point where the current is within 1 % of I_{sc} in the power-producing quadrant.

6.6.3 The variable load should allow the device output power (the product of device current and device voltage) to be varied in increments as small as 0.2 % of the maximum power.

6.6.4 The electrical response time of the variable load should be fast enough to sweep the required range of *I-V* operating points during the measurement period. It is possible that the response time of the device under test may limit how fast the range of *I-V* points can be swept, especially when pulsed simulators are used. For these cases, it may be necessary to make multiple measurements over smaller portions of the *I-V* curve to obtain the entire recommended range.

6.7 *Current Measurement Equipment*—The instrument or instruments used to measure the current through the device under test and the I_{sc} of the reference cell shall have a resolution of at least 0.02 % of the maximum current encountered, and shall have a total error of less than 0.1 % of the maximum current encountered.

6.8 *Voltage Measurement Equipment*—The instrument or instruments used to measure the voltage across the device under test shall have a resolution of at least 0.02 % of the maximum voltage encountered, and shall have a total error of less than 0.1 % of the maximum voltage encountered.

7. Procedures

7.1 *Momentary Illumination Technique*:

7.1.1 This technique is valid for use with pulsed solar simulators, shuttered continuous solar simulators, or shuttered sunlight. For testing under continuous illumination see 7.2.

7.1.2 Determine the spectral mismatch parameter, *M*, using Test Method E 973.

7.1.3 Mount the reference cell and the device to be tested in the test fixture coplanar within ±2°, and normal to the illumination source within ±10°. If an array or module cannot be aligned to within ±10°, the solar angle of incidence, the device orientation and its tilt angle must be reported with the data.

7.1.4 Connect the four-wire Kelvin probe to the module or array output terminals.

7.1.5 Expose the module or array to the light source.

7.1.6 If the temporal instability of the light source (as defined in Specification E 927) is less than 0.1 %, the total irradiance may be determined with the reference cell prior to the performance measurement. In this case, measure the short-circuit current of the reference cell, I_r.

7.1.7 Measure the *I-V* characteristic of the test device by changing the operating point with the variable load so that the provisions of 6.6 are met. At each operating point along the *I-V* characteristic, measure the device voltage, the device current, and I_r.

7.1.7.1 If the provision of 7.1.6 is met, it is not necessary to measure I_r at each operating point.

7.1.8 Measure the temperature of the reference cell, T_r, and the temperature of the test device, T_c. Temperature changes during the test shall be less than 2°C.

7.2 *Continuous Illumination Technique*:

7.2.1 This technique is valid for testing in continuous solar simulators or natural sunlight.

7.2.2 Determine the spectral mismatch parameter, *M*, using Test Method E 973.

7.2.3 Mount the reference cell and the device to be tested in the test fixture coplanar within ±2°, and normal to the illumination source within ±10°. If an array or module cannot be aligned to within ±10°, the solar angle of incidence, the device orientation and its tilt angle must be reported with the data.

7.2.4 Connect the four-wire Kelvin probe to the module or array output terminals.

7.2.5 Expose the test device to the illumination source for a period of time sufficient for the device to achieve thermal equilibrium.

7.2.6 If the temporal instability of the light source (as defined in Specification E 927) is less than 0.1 %, the total irradiance may be determined with the reference cell prior to the performance measurement. In this case, measure the short-circuit current of the reference cell, I_r.

7.2.7 Obtain the average temperature, T_c, of a cell in the module or array using one of the following two methods:

7.2.7.1 For outdoor measurements in natural sunlight if the NOCT correction factors are known (see Annex A1), measure the ambient air temperature and the wind speed. The average wind speed for 5 min preceding the test and during the test should not exceed 1.75 ms $^{-1}$.

7.2.7.2 Measure the temperature of the sensors, following the provisions of 6.5.

7.2.8 Measure the reference cell temperature, T_r.

7.2.9 Measure the *I-V* characteristic of the test device by changing the operating point with the variable load so that the provisions of 6.6 are met. At each operating point along the *I-V* characteristic, measure the device voltage, the device current, and I_r.

7.2.9.1 If the provision of 7.2.6 is met, it is not necessary to measure I_r at each operating point.

7.2.10 Immediately following the *I-V* recording, repeat the temperature measurements and verify that temperature changes during the test were less than 2°C.

8. Calculation of Results

8.1 Adjust the reference cell calibration constant using:

$$C' = \frac{C}{M}\left[1 + \alpha_r(T_r - T_o)\right] \tag{1}$$

8.2 Correct the current at each point of the *I-V* data for irradiance using the following equation:

$$I = I_m \frac{E_o C'}{I_r} \tag{2}$$

where:

I_m = the uncorrected device current as measured in Section 7.

8.3 Calculate the total irradiance during the performance measurement using the following equation (if I_r was measured at each operating point, use the average value of I_r):

$$E = \frac{I_r}{C'} \tag{3}$$

8.4 Determine the uncorrected short-circuit current, I_{scu}, from the *I-V* data using one of the following procedures:

8.4.1 If an *I-V* data pair exists where *V* is 0.0 ± 0.005 V_{oc}, *I* from this pair may be considered to be the short-circuit current.

8.4.2 If the condition in 8.4.1 is not met, calculate the short-circuit current from several *I-V* data pairs where *V* is closest to zero using linear interpolation or extrapolation.

8.5 Determine the uncorrected open-circuit voltage, V_{ocu}, from the *I-V* data measured in Section 7 using one of the following procedures:

8.5.1 If an *I-V* data pair exists where *I* is 0.0 ± 0.001 I_{sc}, *V* from this pair may be considered to be the open-circuit voltage.

8.5.2 If the condition in 8.5.1 is not met, calculate the open-circuit voltage from several *I-V* data pairs where *I* is closest to zero using linear interpolation or extrapolation.

8.6 Translate the uncorrected short-circuit current to RC using the following equation:

$$I_{sc} = \frac{I_{scu}}{[1 + \alpha(E)T_c - \alpha(E_o)T_o]} \tag{4}$$

8.7 Translate the uncorrected open-circuit voltage to RC using the following equation:

$$V_{oc} = \frac{V_{ocu}}{[1 + \beta(E)T_c - \beta(E_o)T_o][1 + \delta(T_c)\ln(E) - \delta(T_o)\ln(E_o)]} \tag{5}$$

NOTE 1—The translation functions α, β, and δ are obtained from experimental determination. An acceptable method is described in Annex A2. Measurement of the translation functions for every device tested is not required; functions previously determined for a device of identical design and construction may be used.

NOTE 2—α and β vary with irradiance, and δ varies with temperature. Eq 4 and Eq 5 account for these variations, although the variations may be small enough that one or more translation functions can be considered constants. In these cases, the translation equations can be simplified.

8.8 Translate each *I-V* data point to RC using the following equations:

$$I_o = I\frac{I_{sc}}{I_{scu}} \tag{6}$$

and:

$$V_o = V\frac{V_{oc}}{V_{ocu}} \tag{7}$$

8.9 Form a table of *P* versus V_o values by multiplying I_o by V_o.

8.10 Find the maximum power point P_m, and the corresponding V_{mp}, in the P versus V_o table. Because of random fluctuations and the probability that one point in the tabular I_o-V_o data will not be exactly on the maximum power point, it is recommended that the following procedure be used to calculate the maximum power point, especially for devices with fill factors greater than 80 %.

8.10.1 Perform a fourth-order polynomial least-squares fit to the P versus V_o data that are within the following limits:

$$0.751_{mp} \leq I_o \leq 1.15I_{mp} \tag{8}$$

and:

$$0.75V_{mp} \leq V_o \leq 1.15V_{mp} \tag{9}$$

These limits are guidelines that have been found to be useful for this procedure and need not be followed precisely. This results in a polynomial representation of P as a function of V_o.

8.10.1.1 It is recommended that a plot of the I_o-V_o data and the polynomial fit be made to visually assess the reliability of the fit.

8.10.1.2 Fewer data points used for the polynomial fit may require the polynomial order to be reduced.

8.10.2 Calculate the derivative polynomial of the polynomial obtained from 8.10.1.

8.10.3 Find a root of the derivative polynomial obtained from 8.10.2 using V_{mp} as an initial guess. An appropriate numerical procedure is the Newton-Horner method with deflation.[4] This root now becomes V_{mp}.

8.10.4 Calculate P_m by substituting the new V_{mp} into the original polynomial from 8.10.1.

8.11 Calculate the fill factor, FF, using the following equation:

$$FF = \frac{P_m}{V_{oc}I_{sc}} \tag{10}$$

9. Report

9.1 The end user ultimately determines the amount of information to be reported. Listed below are the minimum mandatory reporting requirements.

9.2 *Test Module or Array Description*:

9.2.1 Identification,

9.2.2 Physical description,

9.2.3 Area,

9.2.4 Voltage temperature functions, if known,

9.2.5 Current temperature functions, if known,

9.2.6 Voltage irradiance functions coefficient, if known,

9.2.7 Spectral response of the representative cell, in plotted or tabular form, as required for Test Methods E 1021, and

9.2.8 NOCT, C_f, and ΔT functional dependence, if known.

9.3 *Reference Cell Description*:

9.3.1 Identification,

9.3.2 Physical description,

9.3.3 Calibration laboratory,

9.3.4 Calibration procedure (see 6.1.3),

9.3.5 Date of calibration,

9.3.6 Reference spectral irradiance distribution (see 4.3.1),

9.3.7 Spectral response, in plotted or tabular form, as required for Test Methods E 1021, and

9.3.8 Calibration constant.

9.4 *Test Conditions*:

9.4.1 Reporting conditions,

9.4.2 Description and classification of light source (for solar simulators) or ambient temperature, wind speed, solar incidence angle, and geographical location (for outdoor measurements),

9.4.3 Date and time of test,

9.4.4 Spectral mismatch parameter,

9.4.5 Average irradiance measured with reference cell, and

9.4.6 Device temperature, T_c.

9.5 *Test Results*:

9.5.1 Short-circuit current,

9.5.2 Open-circuit voltage,

9.5.3 Maximum power,

9.5.4 Voltage at maximum power,

9.5.5 Fill factor, and

9.5.6 Tabulated and plotted I_o-V_o data.

10. Precision and Bias

10.1 *Interlaboratory Test Program*—An interlaboratory study of module performance measurements was conducted in 1992 through 1994. Seven laboratories performed three repetitions on each of six modules circulated among the participants. The design of the experiment, similar to that of Practice E 691, and a within-between analysis of the data are given in ASTM Research Report No. RR:E44 – 1005.

10.2 *Test Result*— Because *I-V* measurements produce a table of current versus voltage points rather than a single numeric result, the precision analysis was performed on the maximum power point data submitted by the participants. The precision information given below is in percentage points of the maximum power in watts.

10.3 *Precision*:

95 % repeatability limit (within laboratory)	0.7 %
95 % reproducibility limit (between laboratory)	6.7 %

10.4 *Bias*—The contribution of bias to the total error will depend upon the bias of each individual parameter used for the determination of the device performance.

10.4.1 It has been shown that the total bias tends to be dominated by three sources: the reference cell calibration, the spatial uniformity of the light source, and, for efficiency determinations, the area measurement.[5] Bias contributions from instrumentation tend to be, at most, a few tenths of a percent, while bias from the three sources listed here can be as much as ten times greater if the bias is not minimized.

10.4.2 Another source of bias can be hysteresis in the *I-V* data caused by rapid sweeping through the *I-V* curve. This effect, which can result in a value for the maximum power that is either too high or too low, is especially evident in pulsed solar simulator systems.

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[4] Burden, R. L., and Faires, J. D., *Numerical Analysis*, 3rd ed., Prindle, Weber & Schmidt, Boston, MA, 1985, p. 42 ff.

[5] Emery, K. A., Osterwald, C. R., and Wells, C. V., ′′Uncertainty Analysis of Photovoltaic Efficiency Measurements,” *Proceedings of the 19th IEEE Photovoltaics Specialists Conference—1987*, Institute of Electrical and Electronics Engineers, New York, NY, 1987, pp. 153–159.

10.4.3 Loading of the reference cell by the current measurement equipment, that is, non-zero input impedance, can result in measured values of irradiance that are too small. The magnitude of this error will depend on the voltage across the reference cell during the measurements, and the slope of its *I-V* curve near the short-circuit current point.

10.4.4 Measurement of the cell temperature at the back of the device can give a value that is lower than the junction temperature during exposure of the module to the test irradiation. This may result in a value for the voltage slightly too low when translated to RC.

10.4.5 Angular misalignment between the reference cell and the device under test can introduce a bias error. As the angle of incidence of the light source increases, the error due to misalignment increases. The magnitude of this error is equal to the percent difference between $\cos(\theta_i)$ and $\cos(\theta_i + \theta_e)$, where $\theta_i$is the angle of incidence and $\theta_e$is the misalignment angle. If the limits specified in 7.1.3 and 7.2.3 are met, the maximum error is 0.7 %.

11. Keywords

11.1 arrays; modules; performance; photovoltaic; testing

ANNEXES

(Mandatory Information)

A1. METHOD OF DETERMINING THE NOMINAL OPERATING CELL TEMPERATURE (NOCT) OF AN ARRAY OR MODULE

A1.1 Commentary

A1.1.1 The temperature of a solar cell, T_c, is primarily a function of the air temperature, T_a, the average wind velocity, v, the configuration of the module mounting, and the total solar irradiance, E, impinging on the active side of the device. NOCT is defined as the temperature of a device at the conditions of the Nominal Terrestrial Environmental (NTE):

Air temperature	$T_a = 20°C$
Average wind speed	$v = 1\ \text{ms}^{-1}$
Additional conditions are:	
Irradiance	$E = 800\ \text{Wm}^{-2}$
Mounting	oriented normal to solar noon, back either open or closed
Electrical load	open circuit

A1.1.2 The approach for determining NOCT is based on the fact that the temperature difference $(T_c - T_a) = \Delta T$ is largely independent of air temperature and is essentially linearly proportional to the irradiance level. Therefore, a graph of ΔT as a function of E should approximate a straight line. The data can be linearly regressed to obtain a slope and intercept equation of the form:

$$(T_c - T_a) = m \cdot E + b \qquad \text{(A1.1)}$$

where:

m = the slope, and
b = the ΔT intercept.

Setting $E = 800\ \text{Wm}^{-2}$ and $T_a = 20°C$ in this equation, and solving for T_c will yield an uncorrected NOCT value:

$$T_c = \text{NOCT} = m \cdot (800\ \text{Wm}^{-2}) + b + (20°\text{C}) \qquad \text{(A1.2)}$$

A1.1.3 This uncorrected NOCT value is then corrected for wind speed in accordance with Fig. A1.1 to yield the final NOCT value.

A1.1.4 The NOCT test procedure is based on measuring T_c through temperature sensors attached directly to the individual cells in the module over a range of environmental conditions similar to the NTE. The device is tested in a rack so as to simulate use conditions. A plot of ΔT versus E is obtained from a minimum of two field tests in accordance with the following test procedure.

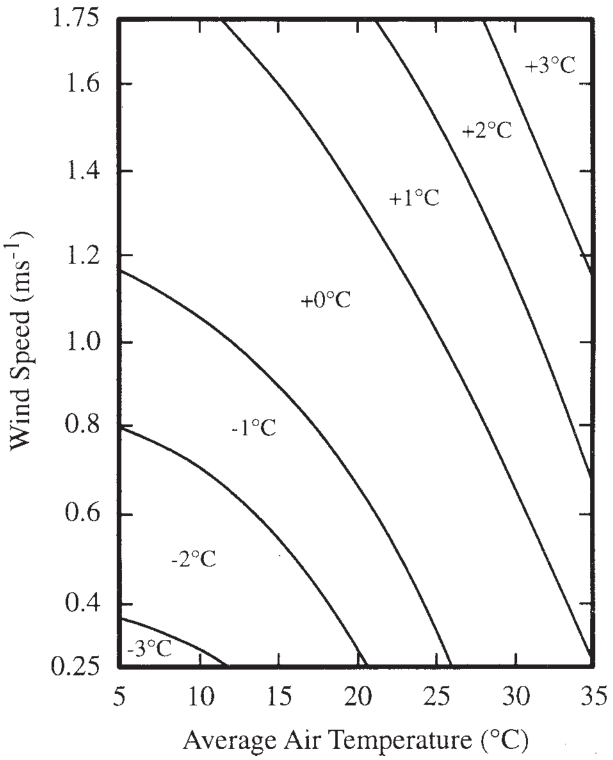

FIG. A1.1 NOCT Correction Factor

A1.2 Apparatus

A1.2.1 *Pyranometer*— A reference pyranometer, as defined by Test Method E 941.

A1.2.2 *Wind Transducer*— Records both the wind direction and the wind speed.

A1.2.3 *Temperature Sensors*—Record air and cell temperatures to within ±1°C.

A1.2.4 *Mountings*—The device must be mounted in a manner similar to the application in which it is to be used, including exposure to or isolation from the wind.

A1.2.5 *Data Recording Equipment*—The response time and scale ranges shall be compatible with the transducers being used.

A1.3 Preparation

A1.3.1 Locate the module to be tested in the interior of a subarray. Black aluminum panels or other modules of the same design must be used to fill in any remaining open area of the subarray structure. Position the plane of the module so that it is normal to the sun within ±5° at solar noon.

A1.3.2 Mount the pyranometer in the same plane as the module and in close proximity to the test module.

A1.3.3 Locate the wind transducer at the approximate height of the module and as near to one of the sides of the module as feasible.

A1.3.4 For ambient air temperature measurement, the temperature sensor must be located at the approximate height of the module. The measurement is made in the shadow of the module.

A1.3.5 For cell temperature measurement, the sensor probes are directly attached to the back of the monitored cells. At least one cell in each quadrant of the module must be measured. Ensure that these cells are not operating in reverse bias.

A1.3.6 Ensure there are no obstructions to prevent full irradiation of the module for a period beginning a minimum of 4 h before and 4 h after solar noon. The ground surrounding the module must not have a high solar reflectance and should be flat or sloping, or both, away from the test fixture. Grass and various types of ground covers, blacktop, and dirt are recommended for the local surrounding area. Buildings having highly reflective surfaces should not be present in the immediate vicinity. Good engineering judgment shall be exercised to ensure that the module front and back sides are receiving a minimum of reflected solar energy from the surrounding area.

A1.3.7 The wind must be predominantly either northerly or southerly; flow parallel to the plane of the array is not acceptable and can result in a low value of NOCT.

A1.3.8 The module terminals are left in an open-circuit condition.

A1.3.9 Clean the active side of the module and the pyranometer bulb before the start of each test. Dirt must not be allowed to build up during the measurement. Cleaning with mild soap solution followed by a rinse with distilled water has proven to be effective.

A1.3.10 A calibration check should be made for all the equipment prior to the start of the test.

A1.4 Procedure

A1.4.1 Acquire a semicontinuous record of ΔT over a one- or two-day period. In addition, irradiance, wind speed, wind direction, and air temperature must be continuously recorded. Record all data approximately every 5 min. Acceptable data consists of measurements made when the average wind speed is 1.0 ± 0.75 ms^{-1} and with gusts less than 4 ms^{-1} for a period of 5 min prior and up to the time of measurement. Local air temperature during the test period shall be 20 ± 15°C.

A1.4.2 Construct a plot from a set of measurements made either prior to solar noon or after solar noon that defines the relationship between ΔT and E.

A1.4.3 Using the plot of ΔT versus E, the value of ΔT at the NTE is determined by interpolating the average value of ΔT for $E = 800$ Wm^{-2}. Use Eq A1.1 to interpolate.

A1.4.4 A correction factor, C_f, to the uncorrected NOCT for average air temperature and wind velocity is determined from Fig. A1.1. This value is added to the uncorrected NOCT and corrects the data to 20°C and 1 ms^{-1}.

A2. METHOD OF DETERMINING CORRECTION FACTORS FOR PHOTOVOLTAIC DEVICES

A2.1 Correction factors for a photovoltaic device are determined from a matrix of open-circuit voltage and short-circuit current values that result from *I-V* measurements of the device made over a range of operating temperatures and incident irradiances.

A2.1.1 It may not be necessary to determine the correction factors for every device to which correction factors are applied; correction factors obtained from another device of identical design and construction may be used.

A2.1.2 It is important to minimize spectral differences in the incident light during these measurements, therefore it is most convenient to perform the measurements using a pulsed solar simulator.

A2.2 The following procedure is recommended for obtaining the V_{oc} and I_{sc} matrices.

A2.2.1 Select the ranges of temperatures and irradiances at which the measurements will be performed. The ranges selected should include the RC that performance measurements are corrected to, and should include temperature and irradiance values at which *I-V* measurements are made. Suggested ranges are 0–80°C and 100–1200 Wm^{-2}. A minimum of six temperatures and six irradiances should be selected for the correction factor measurements, resulting in two 36-element arrays, one each for the V_{oc} and I_{sc} values.

A2.2.2 Device temperature can be varied with a heating apparatus underneath the module. It is recommended that the temperature be increased and held to each value selected in A2.2.1. While the device temperature is held, $V_{oc}$and I_{sc} values are then obtained at each irradiance value, also selected in A2.2.1.

A2.2.3 Incident irradiance can be varied by covering the device with successive layers of screens or thin paper while maintaining the solar simulator irradiance at the maximum irradiance value. The maximum irradiance value should be established and measured with a calibrated reference cell.

A2.2.4 At each temperature and irradiance setting, measure the *I-V* curve of the module and record the resulting V_{oc} and I_{sc} values.

A2.2.5 Calculate the irradiance values from the device I_{sc} data with:

$$E_f = E_u \frac{I_{scf}}{I_{scu}} \quad \text{(A2.1)}$$

where:

E_f = the irradiance on the module while filtered,
E_u = the unfiltered maximum irradiance measured with a reference cell, and
I_{scu} and I_{scf} = the measured short-circuit current values measured with the module unfiltered and filtered, respectively.

The E_f values are calculated for each temperature and averaged to obtain the matrix irradiance indices. This procedure assumes that the filtering and the maximum irradiance at each temperature are identical.

A2.3 Calculate the slope of I_{sc}versus temperature, $\Delta I_{sc}/\Delta T$, at each irradiance level using a linear least-squares fit of the data obtained in A2.2. These will be used for the calculation of the current temperature function, $\alpha(E)$.

A2.4 Calculate the slope of V_{oc}versus temperature, $\Delta V_{oc}/\Delta T$, at each irradiance level using a linear least-squares fit of the data obtained in A2.2. These will be used for the calculation of the voltage temperature function, $\beta(E)$.

A2.5 Calculate the slope of V_{oc}versus the natural logarithm of the irradiance, $\Delta V_{oc}/\Delta \ln E$, for each module temperature using a linear least-squares fit of the data obtained in A2.2. These will be used for the calculation of the voltage irradiance correction function, $\delta(E)$.

A2.6 Obtain normalization factors for the slopes obtained in A2.3-A2.5. These factors are the values of I_{sc} and V_{oc} in the data matrices at the temperature and irradiance values corresponding to the RC device performance will be corrected to. Using the linear fits obtained in A2.3 and A2.4, and linear interpolation, if necessary, calculate the I_{sc} and V_{oc} at the standard reporting conditions. Divide the slopes obtained in A2.3-A2.5 by the appropriate normalization factor.

A2.7 The correction factors α and β vary with irradiance (β varies as the natural logarithm of irradiance), and δ varies with temperature. For silicon devices, β and δ change only about 10 % over the ranges suggested in A2.2.1, while α can vary by a factor of 5 or more. The translation equations in 8.6 and 8.7 are formulated with variable correction functions, even though they may be used as constants. The following procedures calculate the functional forms of the correction factors. Constant values can then be obtained by evaluating the functions at points in the middle of the temperature and irradiance ranges.

A2.7.1 Perform a linear least-squares fit of the normalized $\Delta I_{sc}/\Delta T$ slopes versus irradiance. The resulting linear equation is the current correction function, $\alpha(E)$.

A2.7.2 Perform a logarithmic least-squares fit of the normalized $\Delta V_{oc}/\Delta T$ slopes versus irradiance. The resulting logarithmic equation is the voltage correction function, $\beta(E)$.

A2.7.3 Perform a linear least-squares fit of the normalized $\Delta V_{oc}/\Delta \ln E$ slopes versus temperature. The resulting linear equation is the voltage irradiance correction function, $\delta(T)$.

A2.8 It is recommended that the matrix of V_{oc} and I_{sc}values used to determine the correction functions be retained and reported with the results so that the functions can be recalculated or normalized to a different set of reporting conditions.